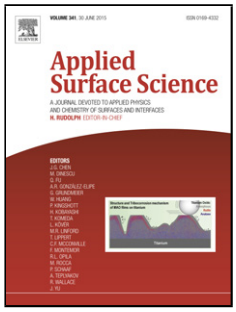

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A Perspective on Two Chemometrics Tools: PCA and MCR, and Introduction of a New One: Pattern Recognition Entropy (PRE), As Applied to XPS and ToF-SIMS Depth Profiles of Organic and Inorganic Materials

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